RAM Mounts Testing Summary

RAM® Powered Dock for Honeywell CT40/45/47

Products Covered

RAM-HOL-HON12PDHLU
RAM-HOL-HON12PDHU
RAM-HOL-HON12PDLU
RAM-HOL-HON12PDU
RAM-HOL-HON12PHLU
RAM-HOL-HON12PHU
RAM-HOL-HON12PLU
RAM-HOL-HON12PU
RAM-HOL-HON12U
RPR-101-HON12BC
RPR-101-HON12TC

Accompanying Power Supplies

RAM-GDS-CHARGE-M55-V7B1U
RAM-GDS-CHARGE-M55-V8BU

Test	Description
Vibration – operational	Unlocked Dock: MIL-STD-810H, Method 514.8, Table 514.8C-I, Category 4. (US Highway Truck Profile) Locked Dock: MIL-STD-810H, Method 514.8, Table 514.8C-VII, Category 4. (Composite Wheeled Vehicle Profile) Test performed with dock and device oriented vertical, transverse, and longitudinal. 1 hour each axis, 3 hours total.
Functional Shock - operational	Locked Dock: MIL-STD-810H, Method 516.8, Procedure 1, 3 positive and 3 negative pulses per vertical, longitudinal, and transverse axis. 18 total pulses. Pulses are 20G, 11ms terminal peak sawtooth. *If using in shock environments greater than 11G, use the locked position.
Pogo Pins – Cycle rating	Pogo pins rated to 100k cycles
USB Validation Protocol, Speed, Power	NPI Developed Testing Specification for USB 2.0 Compliance up to 480Mbps, 4.75-5.25VDC @ 900mA per port
Power Supply Input Voltage Tolerance	NPI Developed Testing Specification for Cycle Testing of Input Voltage and variable current
Power Supply Output Voltage Tolerance	NPI Developed Testing Specification for Cycle Testing of Output Voltage and variable current
Power Supply Load Test	NPI Developed Testing Specification for Cycle Testing of Output Voltage and variable current
Regulatory Compliance	FCC, IC CE, RoHS, WEEE
Safety, Emission, Immunity (Ram Power Supply)	CE EN:55032, EN 55035, IEC 61000-6-1, EN 62368-1, e-Mark

Official NPI testing documentation. Tests performed onsite by NPI engineers.